

A BIST scheme for testing mixed analogue and digital circuits

Robson, Malcolm; Russel, Gordon BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 183-186: ill

A new modified berger code for concurrent error detection

Maamar, Ali H.; Russel, Gordon BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 187-190: ill